

[54] **CIRCUIT TESTER**

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[73] Assignee: **General Electric Company**

[\*\*] Term: **14 Years**

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[52] U.S. Cl. .... **D10/78**

[58] Field of Search ..... **D10/75, 78, 79, 46;  
340/641; 315/58, 71, 291; 324/51, 72.5, 73 R,  
122, 133, 149, 156**

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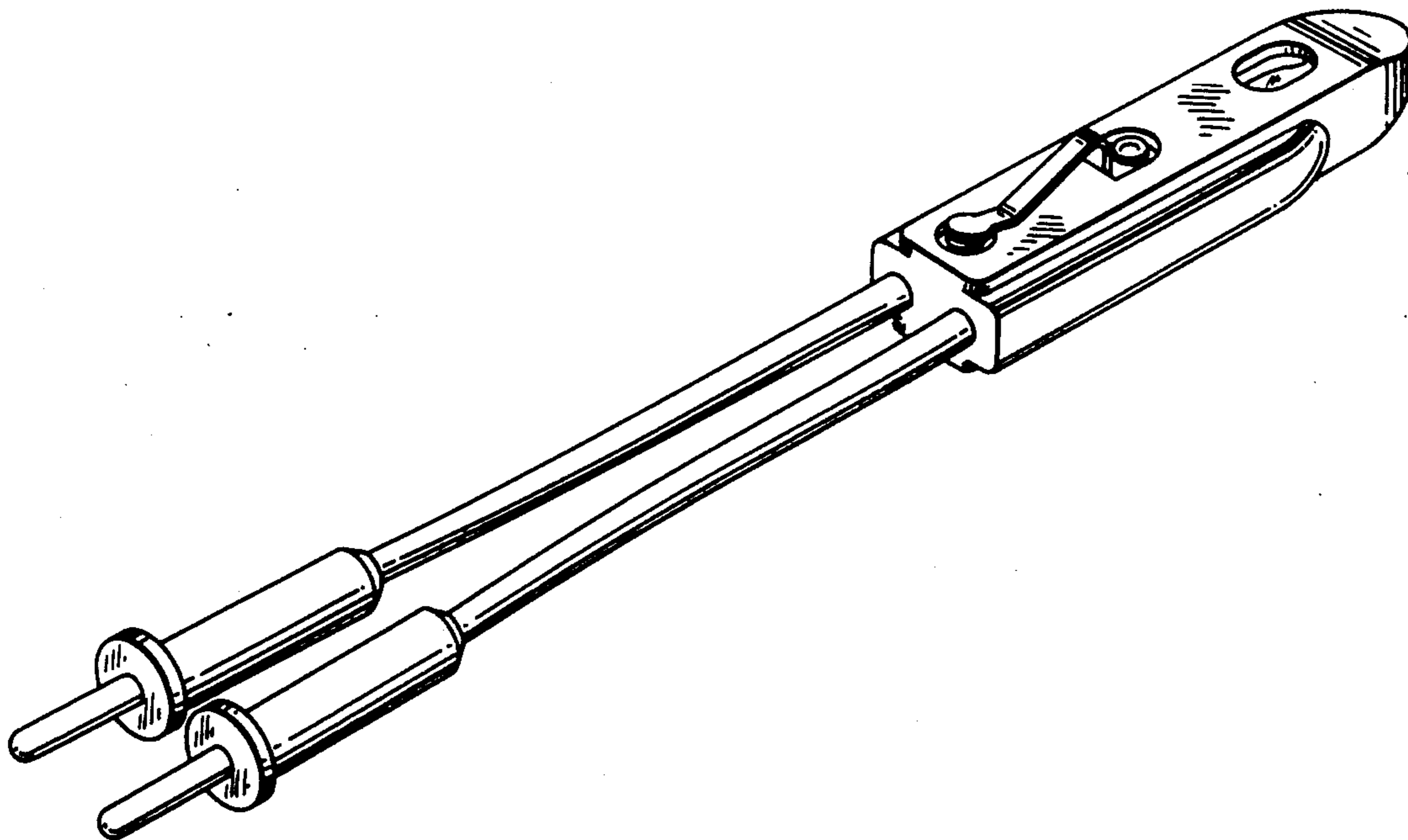
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[57] **CLAIM**

The ornamental design for a circuit tester, as shown and described.

**DESCRIPTION**

FIG. 1 is a right front perspective view of a circuit tester showing our new design;  
 FIG. 2 is a front elevational view thereof;  
 FIG. 3 is a rear elevational view thereof;  
 FIG. 4 is a right side elevational view thereof, the left side being a mirror image thereto;  
 FIG. 5 is a bottom plan view thereof;  
 FIG. 6 is a top plan view thereof.



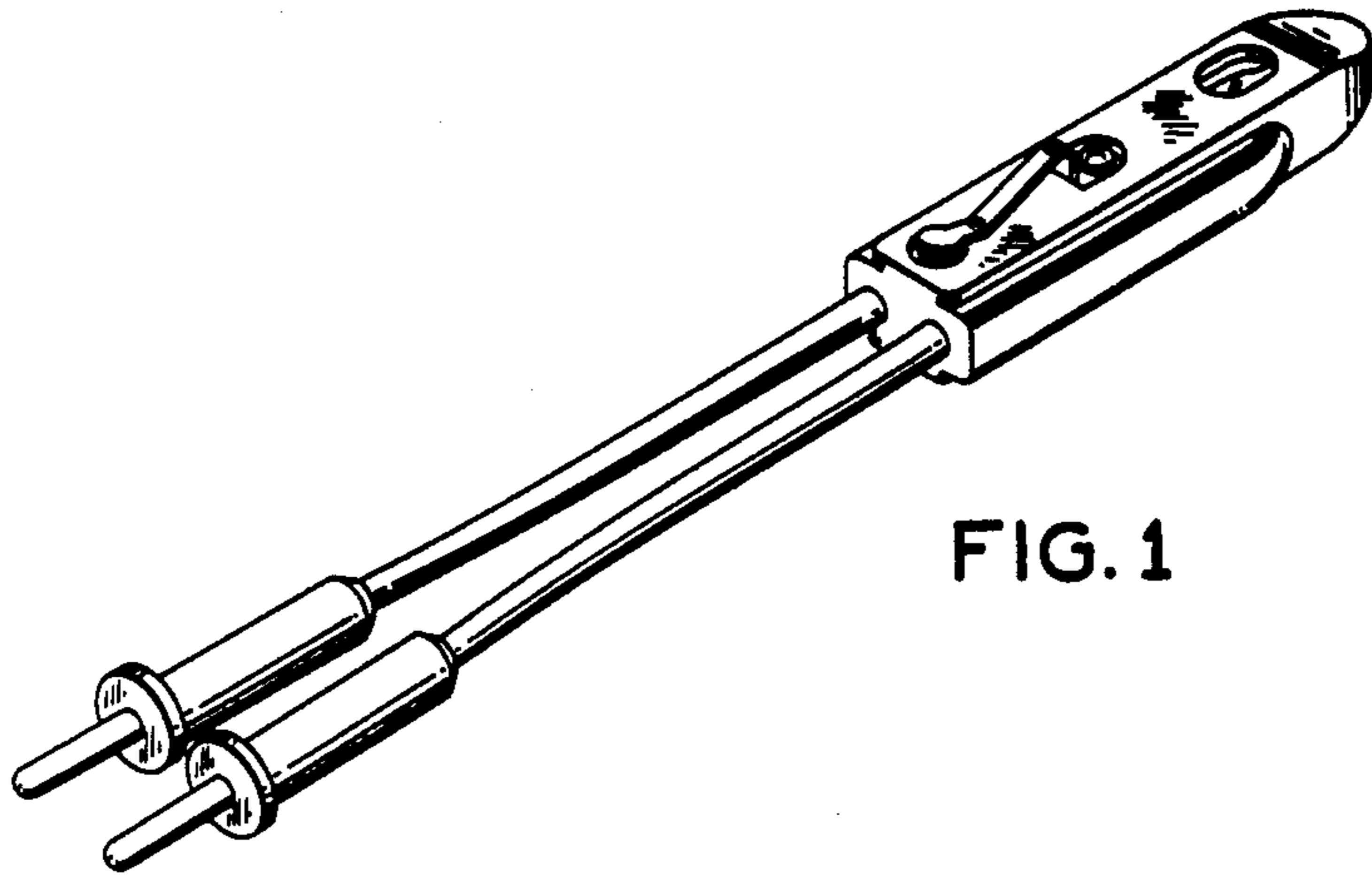


FIG. 1



FIG. 2



FIG. 3



FIG. 4

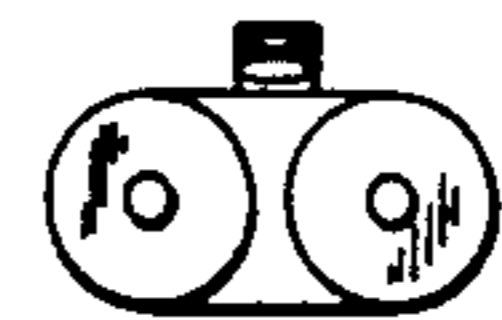


FIG. 5



FIG. 6